



$V_{RSM}$ V	$V_{RRM}, V_{DRM}$ V	$I_{TRMS} = 275$ A (maximum value for continuous operation) $I_{TAV} = 172$ A (sin 180; $T_C = 86$ °C)	
1500	1400	AMKT 172-14E	
1700	1600	AMKT 172-16E	
1900	1800	AMKT 172-18E	

Symbols and parameters			Values	Units
$I_{TAV}$	Average on-state current	sin. 180; $T_C = 85$ (100)°C	175 (124)	A
$I_{TSM}$	Surge on-state current	$T_{vj} = 25$ °C; 10 ms	5400	A
		$T_{vj} = 125$ °C; 10 ms	5000	A
$I^2t$	$I^2t$ value, rating for fusing	$T_{vj} = 25$ °C; 10 ms	145000	A <sup>2</sup> s
		$T_{vj} = 125$ °C; 10 ms	125000	A <sup>2</sup> s
$V_T$	On-state voltage	$T_{vj} = 25$ °C; $I_T = 500$ A	max. 1.41	V
$V_{T(TO)}$	On-state threshold voltage	$T_{vj} = 125$ °C	max. 0.83	V
$r_T$	On-state slope resistance	$T_{vj} = 125$ °C	max. 1.3	mΩ
$V_{T(TO)(typ)}$	On-state threshold voltage	$T_{vj} = 125$ °C	0.8	
$r_{T(typ)}$	On-state slope resistance	$T_{vj} = 125$ °C	1.2	
$I_{DD}; I_{RD}$	Forward off-state current; Direct reverse current	$T_{vj} = 125$ °C, $V_{RD} = V_{RRM}; V_{DD} = V_{DRM}$	max. 40	mA
$t_{gd}$	Gate controlled turn-on delay time	$T_{vj} = 25$ °C; $I_G = 1$ A; $di_G/dt = 1$ A/μs	1	μs
$t_{gr}$	Gate controlled rise time	$V_D = 0.67 * V_{DRM}$	2	μs
$(di/dt)_{cr}$	Critical rate of rise of on-state current	$T_{vj} = 125$ °C	max. 200	A/μs
$(dv/dt)_{cr}$	Critical rate of rise of off-state voltage	$T_{vj} = 125$ °C	max. 1000	V/μs
$t_q$	Turn-off time	$T_{vj} = 125$ °C	typ. 175	μs
$I_H$	Holding current	$T_{vj} = 25$ °C; typ. / max	150 / 400	mA
$I_L$	Latching current	$T_{vj} = 25$ °C; $R_G = 33$ Ω; typ. / max	300 / 1000	mA
$V_{GT}$	Gate trigger voltage	$T_{vj} = 25$ °C; d.c.	min. 2	V
$I_{GT}$	Gate trigger current	$T_{vj} = 25$ °C; d.c.	min. 150	mA
$V_{GD}$	Gate non-trigger voltage	$T_{vj} = 125$ °C; d.c.	max. 0.25	V
$I_{GD}$	Gate non-trigger current	$T_{vj} = 125$ °C; d.c.	max. 10	mA
$R_{th(j-c)}$	Thermal resistance, junction to case	cont. DC; per chip / per module	0.155 / 0.078	K/W
		sin.180; per chip / per module	0.164 / 0.082	K/W
		rec.120; per chip / per module	0.18 / 0.09	K/W
$R_{th(c-s)}$	Thermal resistance, junction to heatsink	per chip / per module	0.1 / 0.05	K/W
$T_{vj}$	Virtual junction temperature		-40 ... +125	°C
$T_{stg}$	Storage temperature range		-40 ... +125	°C
$V_{ISOL}$	Insulation test voltage (r.m.s.)	a.c. 50 Hz; r.m.s.; 1s / 1min.	3600 / 3000	V~
$M_s$	Mounting torque on heatsink	min / max	5 ± 15 %	Nm
$M_t$	Mounting torque for terminals	min / max	5 ± 15 %	Nm
$a$	Maximum allowable acceleration		5*9.81	m/s <sup>2</sup>
$W$	Weight	approx.	165	g

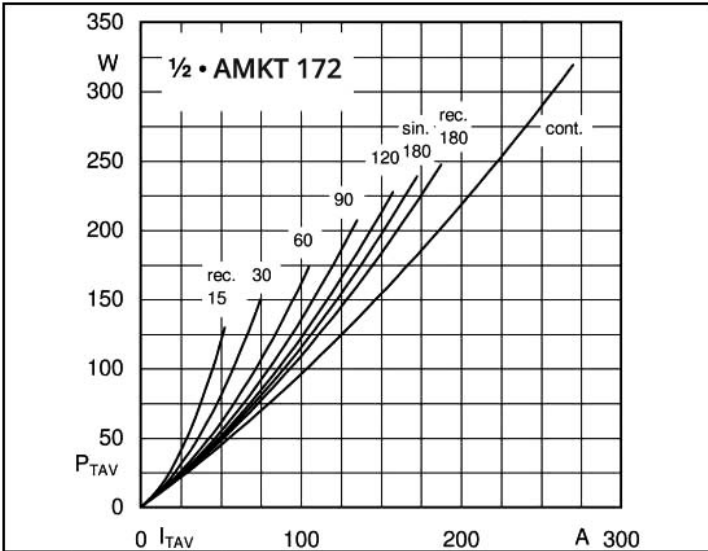


Fig. 1L Power dissipation per thyristor vs. on-state current

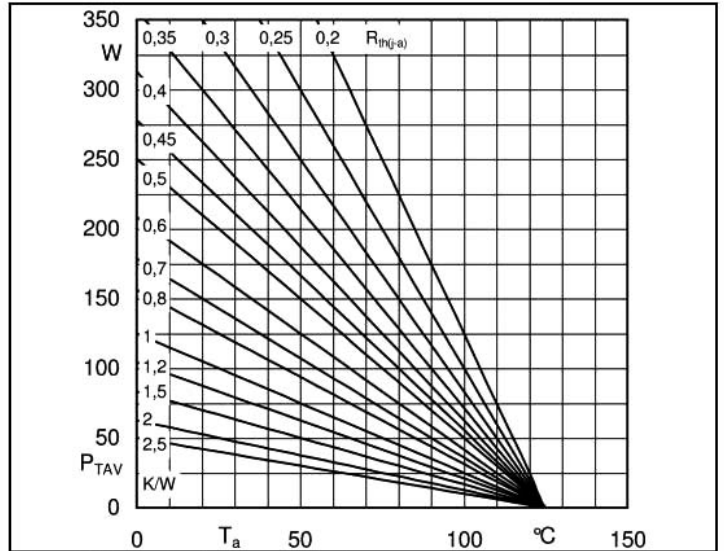


Fig. 1R Power dissipation per thyristor vs. ambient temp.

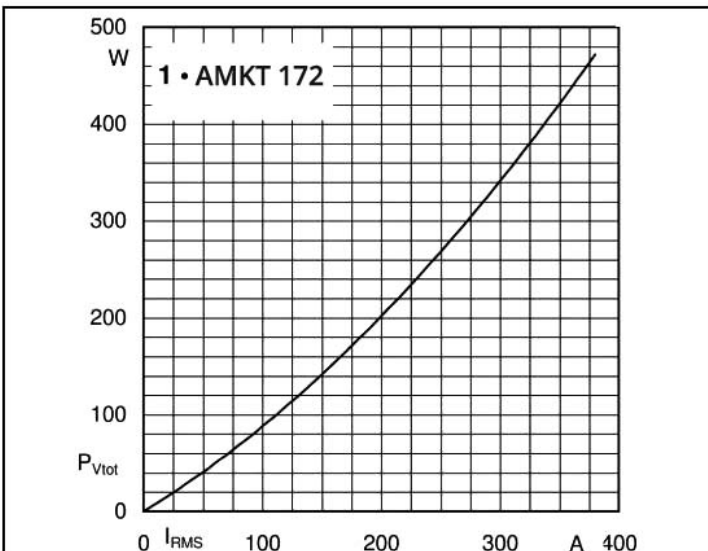


Fig. 2L Power dissipation per module vs. rms current

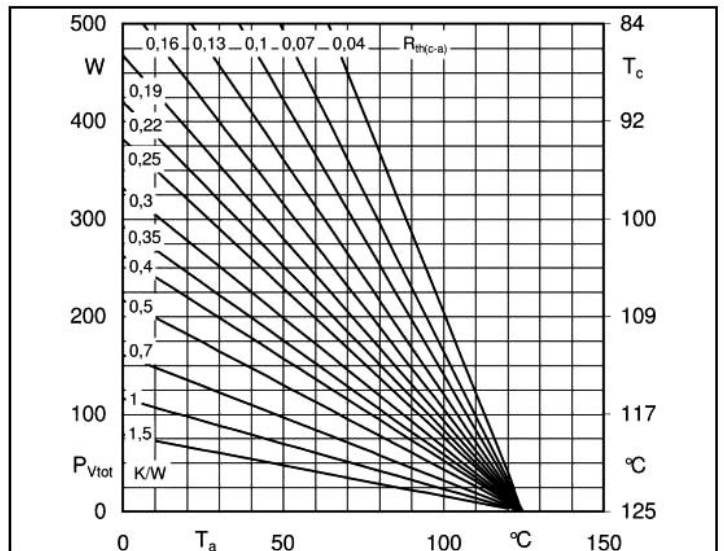


Fig. 2R Power dissipation per module vs. case temp.

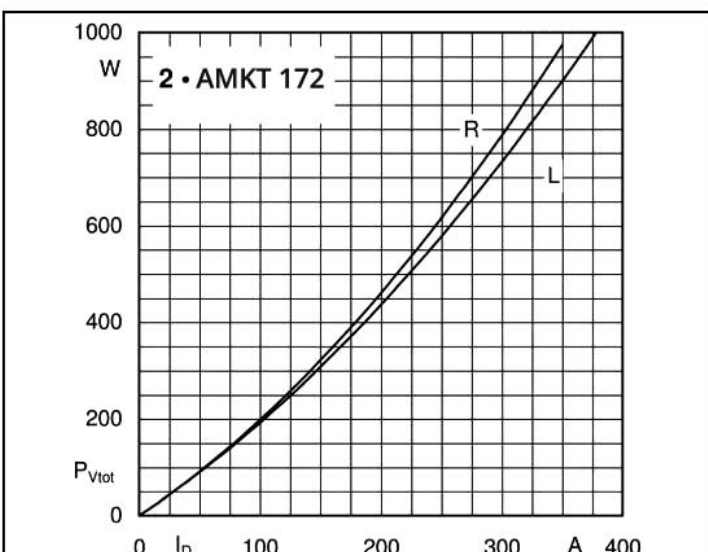


Fig. 3L Power dissipation of two modules vs. direct current

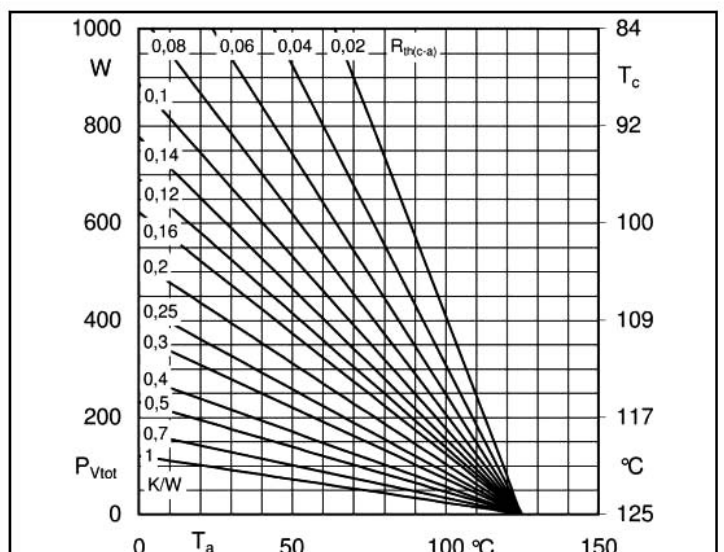


Fig. 3R Power dissipation of two modules vs. case temp.

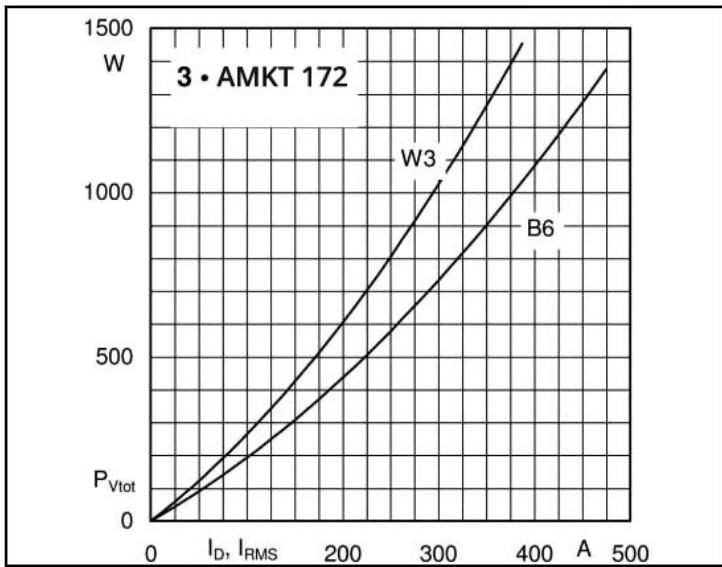


Fig. 4L Power dissipation of three modules vs. direct and rms current

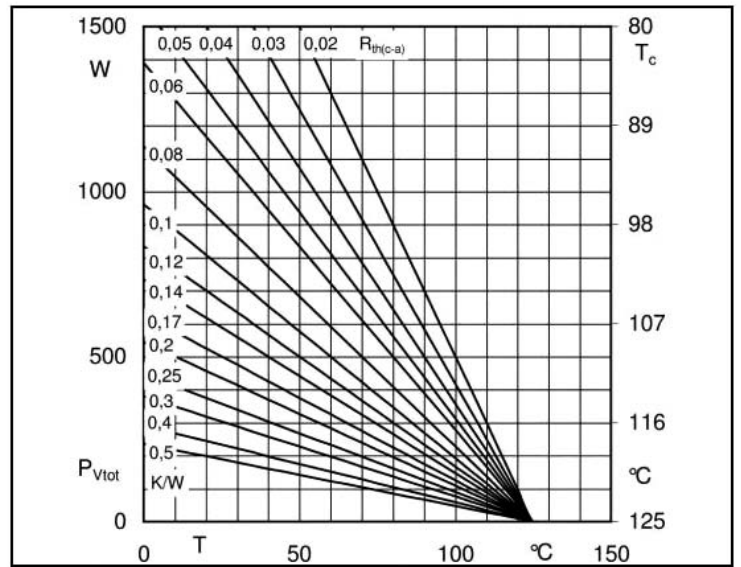


Fig. 4R Power dissipation of three modules vs. case temp.

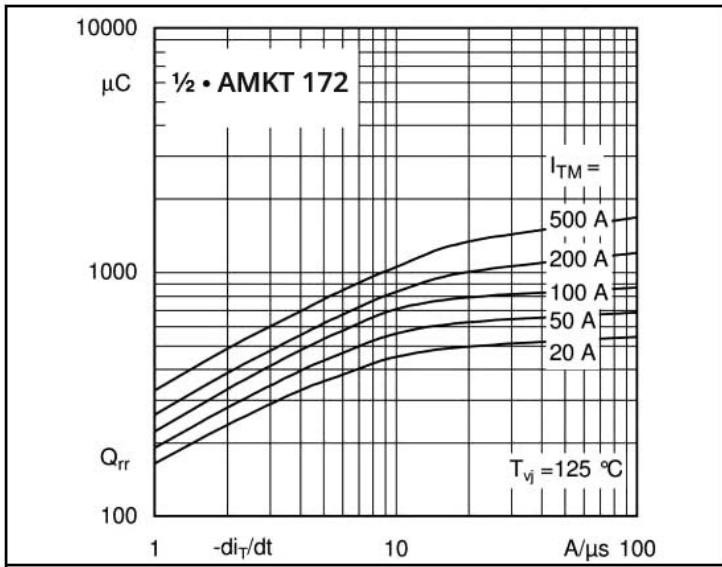


Fig. 5 Recovered charge vs. current decrease

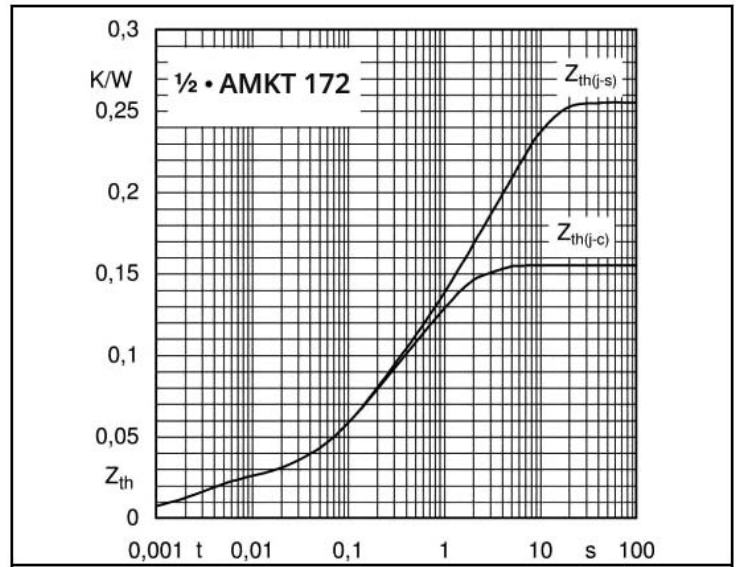


Fig. 6 Transient thermal impedance vs. time

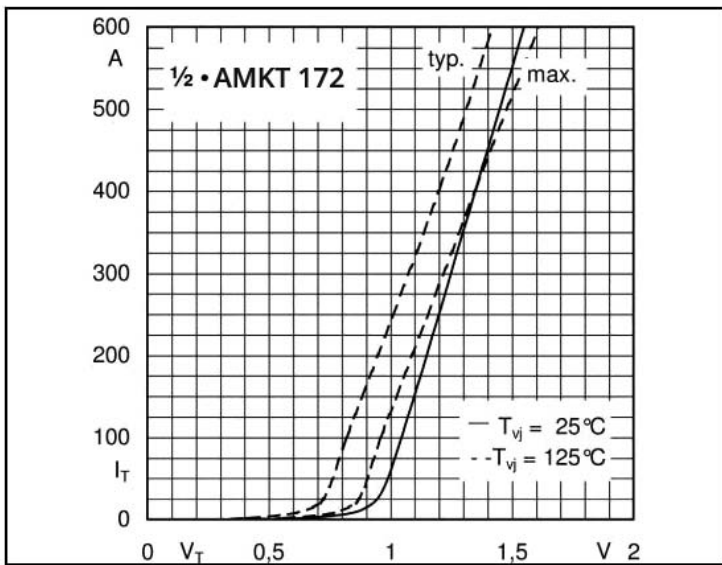


Fig. 7 On-state characteristics

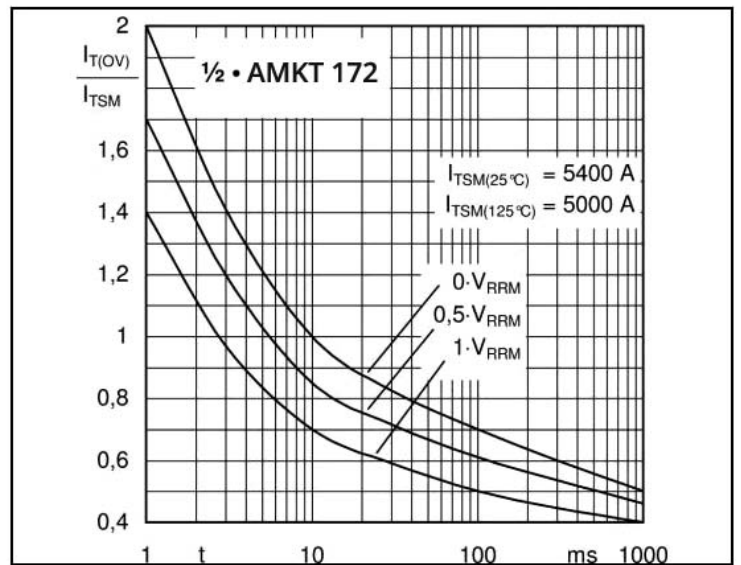
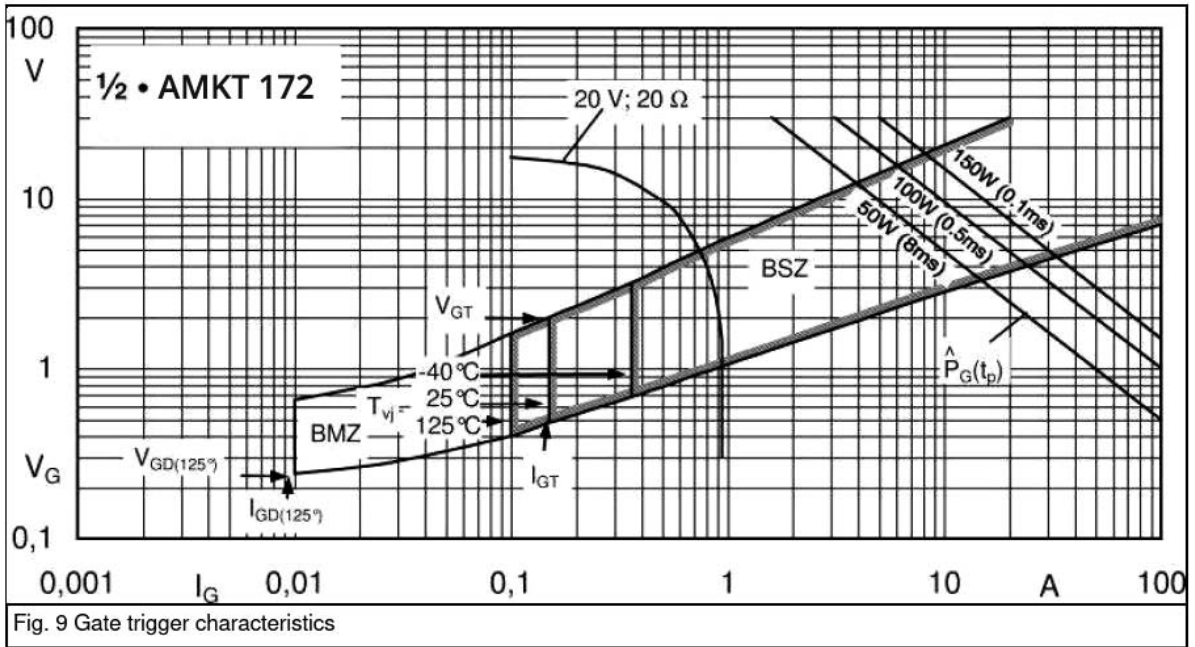
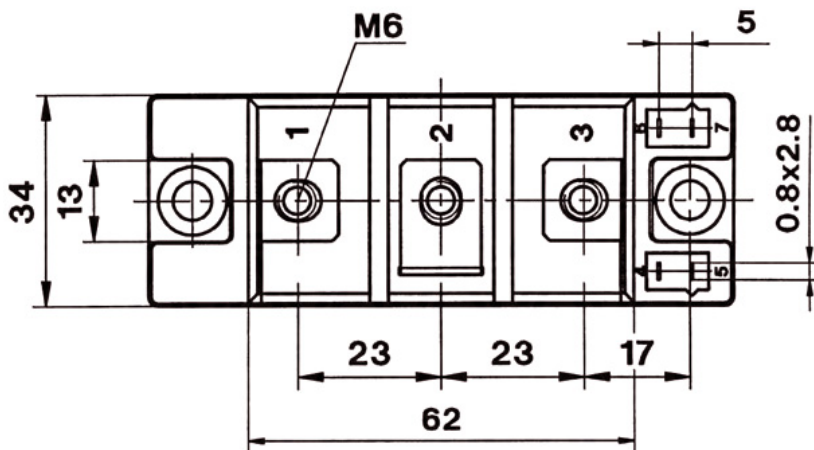
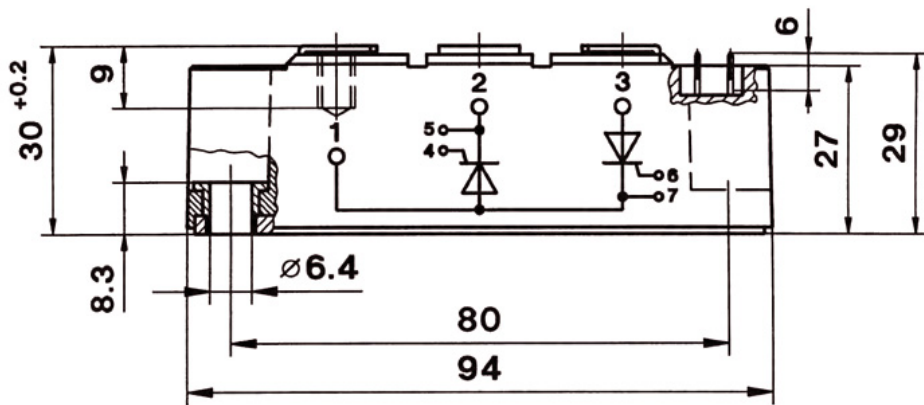


Fig. 8 Surge overload current vs. time



**DIMENSIONS**



Dimensions in mm

**TOPOLOGY OF INTERNAL CONNECTION**

